

ANNOUNCEMENT

Symposium on Surface Contamination: Its Genesis, Detection and Control

September 10-14, 1978, Washington, D.C.

This symposium will be held at the Fourth International Conference on Contamination Control (under the auspices of the International Committee of Contamination Control Societies).

Surface contamination is of concern to everyone dealing with surfaces, and the world of surfaces is wide and open-ended. Surface contamination can originate from a number of sources and is present either in film form or as particulate.

The purpose of this symposium is to bring together scientists and engineers interested in all aspects of surface contamination. Papers dealing with all types of surface contaminants irrespective of the nature of the surface are solicited.

All prospective authors are urged to indicate their intention to submit a paper by writing to:

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